L Number	Hits	Search Text	DB	Time stamp
1	70627	(programmable with logic) pla pga fpga	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 15:49
2	19587	((programmable with logic) pla pga fpga) same memory	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 15:50
3	254	((programmable with logic) pla pga fpga) same (self near3 test)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 15:50
4	137	((programmable with logic) pla pga fpga) same (self near3 test) and bus	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 15:51
6	5	(((programmable with logic) pla pga fpga) same (self near3 test) and bus) not (((programmable with logic) pla pga fpga) same (self near3 test) and bus and block)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 15:51
5	132	((programmable with logic) pla pga fpga) same (self near3 test) and bus and block	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 16:16
9	13	"773104"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 16:16
-	224955	programmable	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/02 18:13
-	36710	programmable near2 logic	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 12:43
-	15	(programmable near2 logic) and self?repair	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/02 18:20

-	1967	(programmable near2 logic) and repair	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/02 18:20
-	20	(programmable with logic) and self?repair	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 14:22
-	100	("6067262" "6367042" "6651202" "6667917" "5956350" "5987632" "5920515" "6560740" "6065134" "5909404" "6300769" "6505308" "6505313" "6640321" "6691264" "6085334" "6408401" "6691252" "5577050" "5982681" "6304989" "6425103" "5764878" "5659551" "6405331" "6728910" "5748543" "6373758" "6574757" "5991907" "6003150" "5668815" "6073258" "4918378" "5006787" "5546406" "5968192" "6044481" "5404359" "5760643" "5936876" "5969538" "5994912" "6046600" "6166557" "6768694" "6154864" "6246617" "6438046" "6496947").pn. ("6202182" "6182257" "6667918" "5375091" "5675545" "5383195" "5425035" "5822228" "5471482" "6151692" "6510530" "5572712" "5805789" "5745500" "6018484" "6185138" "5355369" "6167544" "6341092" "6631086" "5570374" "5961653" "5677913" "5751729" "6108252" "6249893" "5313470" "5661732" "5668947" "5784382" "5862151" "5825785" "5963566" "6718496" "5991909" "5485467" "6292912" "5668817" "5383143" "5260950" "5570375" "5796745" "5230000" "5416783" "5416784" "5513190" "5533032" "5553082" "5612963" "5761489").pn.	USPAT	2004/08/03 15:54
-	46175	programmable with logic	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 12:43
-	10972	(programmable with logic) and (self?repair BISR repair replace replacement spare)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 16:36

-	100	("6067262" "6367042" "6651202" "6667917" "5956350" "5987632" "5920515" "6560740" "6065134" "5909404" "6300769" "6505308" "6505313" "6640321" "6691264" "6085334" "6408401" "6691252" "5577050" "5982681" "6304989" "6425103" "5764878" "5659551" "6405331" "6728910" "5748543" "6373758" "6574757" "5991907" "6003150" "5668815" "6073258" "4918378" "5006787" "5546406" "5968192" "6044481" "5404359" "5760643" "5936876" "5969538" "5994912" "6046600" "6166557" "6768694" "6154864" "6246617" "6438046" "6496947").pn. ("6202182" "6182257" "6667918" "5375091" "5675545" "5383195" "5425035" "5822228" "5471482" "6151692" "6510530" "5572712" "5805789" "5745500" "6018484" "6185138" "5355369" "6167544" "6341092" "6631086" "5570374" "5961653" "5677913" "5751729" "6108252" "6249893" "5313470" "5661732" "5668947" "5784382" "5862151" "5825785" "5963566" "6718496" "5991909" "5485467" "6292912" "5668817" "5383143" "5260950" "5570375" "5796745" "5230000" "5416783" "5416784" "5513190" "5533032" "5553082" "5612963" "5761489").pn.	USPAT	2004/08/03 16:36

| - | 12 | ((programmable with logic) and (self?repair BISR repair replace replacement spare)) and (("6067262" "6367042" "6651202" "6667917" "5956350" "5987632" "5920515" "6560740" "6065134" "5909404" "6300769" "6505308" "6505313" "6640321" "6691264" "6085334" "6408401" "6691252" "5577050" "5982681" "6304989" "6425103" "5764878" "5659551" "6405331" "6728910" "5748543" "6373758" "6574757" "5991907" "6003150" "5668815" "6073258" "4918378" "5006787" "5546406" "5968192" "6044481" "5404359" "5760643" "5936876" "5969538" "5994912" "6046600" "6166557" "6768694" "6154864" "6246617" "6438046" "6496947").pn. ("6202182" "6182257" "6667918" "5375091" "5675545" "5383195" "5425035" "5822228" "5471482" "6151692" "6510530" "5572712" "5805789" "5745500" "6018484" "6185138" "5355369" "6167544" "6341092" "6631086" "5570374" "5961653" "5677913" "5751729" "6108252" "6249893" "5313470" "5661732" "5668947" "5784382" "5862151" "5825785" "5963566" "6718496" "5991909" "5485467" "6292912" "5668817" "5383143" "5260950" "5570375" "5796745" "5230000" "5416783" "5416784" "5513190" "5533032" "5553082" "5612963" "5761489").pn.) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/08/03 18:44 |
| - | 10972 | (programmable with logic) and (self?repair BISR repair replace replacement spare) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2004/08/03 16:37 |

-	100	("6067262" "6367042" "6651202" "6667917" "5956350" "5987632" "5920515" "6560740" "6065134" "5909404" "6300769" "6505308" "6505313" "6640321" "6691264" "6085334" "6408401" "6691252" "5577050" "5982681" "6304989" "6425103" "5764878" "5659551" "6405331" "6728910" "5748543" "6373758" "6574757" "5991907" "6003150" "5668815" "6073258" "4918378" "5006787" "5546406" "5968192" "6044481" "5404359" "5760643" "5936876" "5969538" "5994912" "6046600" "6166557" "6768694" "6154864" "6246617" "6438046" "6496947").pn. ("6202182" "6182257" "6667918" "5375091" "5675545" "5383195" "5425035" "5822228" "5471482" "6151692" "6510530" "5572712" "5805789" "5745500" "6018484" "6185138" "5355369" "6167544" "6341092" "6631086" "5570374" "5961653" "5677913" "5751729" "6108252" "6249893" "5313470" "5661732" "5668947" "5784382" "5862151" "5825785" "5963566" "6718496" "5991909" "5485467" "6292912" "5668817" "5383143" "5260950" "5570375" "5796745" "5230000" "5416783" "5416784" "5513190" "5533032" "5553082" "5612963" "5761489").pn.	USPAT	2004/08/03 16:37
-	2227	macrocell	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/04 11:51
-	4	hard adj macrocell	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 18:45
-	701	macrocell and test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/04 11:51
-	74	macrocell and BIST	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/04 11:51
-	60	macrocell and BIST and (repair replace replacement spare)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/04 11:52

-	0	03256461.9		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/06 16:17
-	0	3256461.9		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/06 16:17
-	7	"3256461"		USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/06 16:17

L Number	Hits	Search Text	DB	Time stamp
-	55977	memory with (test testing tester tested)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:22
-	22252	(memory with (test testing tester tested)).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:18
-	6371	memory with (test testing tester tested) and feedback	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:22
-	751	memory with (test testing tester tested) and (feedback near3 path)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:23
-	949	memory with (test testing tester tested) and (feedback with path)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:39
-	0	memory with (test testing tester tested) and (feedback with path) and BISR	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:32
-	104	memory with (test testing tester tested) and (feedback with path) and repair	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 13:59
-	100372	bit near3 (latch capacity storage register)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:37
-	482	(memory with (test testing tester tested) and (feedback with path)) and (bit near3 (latch capacity storage register))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:37

-		50	("6667917" "6067262" "5956350" "6367042" "6651202" "5920515" "6560740" "6304989" "5987632" "5909404" "6425103" "6505308" "4918378" "5006787" "6300769" "6505313" "6640321" "6373758" "5675545" "6065134" "6249893" "5862151" "5982681" "5425035" "5577050" "5258986" "5761215" "6185709" "5748543" "6085334" "6408401" "6691252" "6718496" "5968192" "6044481" "5471482" "5936876" "6018484" "6185138" "6151692" "6167544" "6510530" "6249889" "5825785" "5668947" "5724367" "5784382" "6341092" "6388930" "5640509").pn.	USPAT	2004/05/26 12:08

-	2	6691937.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:44
-	3	flare adj register	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 12:17
-	11	flare near3 register	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 19:36
-	37	flare with register	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 12:19
-	3	flare with register and bisr	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 17:28
-	164	(scan adj (latch path chain)) with feedback	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 12:43

-		1	((scan adj (latch path chain)) with feedback) and (("6667917" "6067262" "5956350" "6367042" "6651202" "5920515" "6560740" "6304989" "5987632" "5909404" "6425103" "6505308" "4918378" "5006787" "6300769" "6505313" "6640321" "6373758" "5675545" "6065134" "6249893" "5862151" "5982681" "5425035" "5577050" "5258986" "5761215" "6185709" "5748543" "6085334" "6408401" "6691252" "6718496" "5968192" "6044481" "5471482" "5936876" "6018484" "6185138" "6151692" "6167544" "6510530" "6249889" "5825785" "5668947" "5724367" "5784382" "6341092" "6388930" "5640509").pn.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 12:25

-	138	(scan adj (path chain)) with feedback	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 13:57
-	2	re$load with (scan adj (path chain))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 14:42
-	44	memory with (test testing tester tested) and (feedback with path) and repair and scan	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 14:04
-	50	memory with (test testing tester tested) and ((feedback) same scan) and repair	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 14:05
-	99	re$load with scan	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 14:42
-	2475	linear adj feedback adj shift adj register	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 17:29
-	15202	parallel near2 load	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 17:29
-	84	(linear adj feedback adj shift adj register) and (parallel near2 load)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 19:13
-	329	zerbe.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 19:14
-	35	zerbe.in. and jared.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 19:14

		3	PURI.in. and MUKESH.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 19:36

Original Classifications
 18 714/733
 12 365/201
  9 714/718
  6 714/7
  5 365/200
  5 714/30
  5 714/725
  5 714/732
  4 714/727
  3 324/763
  2 714/710
  2 714/711
  2 714/719
  2 714/720
  2 714/724

Cross-Reference Classifications
 26 714/733
 14 365/201
 11 714/718
  9 714/30
  7 365/200
  7 714/726
  6 714/732
  6 714/734
  5 714/724
  5 714/738
  4 714/710
  4 714/711
  4 714/719
  4 714/736
  3 714/42
  3 714/6
  2 324/73.1
  2 324/765
  2 365/225.7
  2 365/230.03
  2 365/230.06
  2 365/236
  2 708/250
  2 714/720
  2 714/723
  2 714/725

```
2  714/727
2  714/731
2  714/739
2  714/8
2  716/16
```

Combined Classifications
```
44  714/733
26  365/201
20  714/718
14  714/30
12  365/200
11  714/732
 8  714/726
 7  714/7
 7  714/724
 7  714/725
 6  714/710
 6  714/711
 6  714/719
 6  714/727
 6  714/734
 6  714/738
 4  324/763
 4  714/720
 4  714/736
 3  324/73.1
 3  324/765
 3  365/225.7
 3  714/42
 3  714/6
 3  714/723
 3  714/739
 2  365/230.03
 2  365/230.06
 2  365/236
 2  708/250
 2  714/731
 2  714/8
 2  716/16
```

Titles of Most Frequently Occurring Classifications of Patents Returne
d

From A Search of 10002499 on August 03, 2004


```
44   714/733        (18 OR, 26 XR)
        Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699           PULSE OR DATA ERROR HANDLING
        714/724           .Digital logic testing
        714/733           ..Built-in testing circuit (BILBO)


26   365/201        (12 OR, 14 XR)
        Class    365 :   STATIC INFORMATION STORAGE AND RETRIEVAL
        365/189.01        READ/WRITE CIRCUIT
        365/201           .Testing


20   714/718        (9 OR, 11 XR)
        Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699           PULSE OR DATA ERROR HANDLING
        714/718           .Memory testing


14   714/30         (5 OR, 9 XR)
        Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/100           DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

        714/1             .Reliability and availability
        714/25            ..Fault locating (i.e., diagnosis or testing)

        714/27            ...Particular access structure
        714/30            ....Built-in hardware for diagnosing or testin
g
                          within-system component (e.g., microprocess
or test mode
                          circuit, scan path)


12   365/200        (5 OR, 7 XR)
        Class    365 :   STATIC INFORMATION STORAGE AND RETRIEVAL
        365/189.01        READ/WRITE CIRCUIT
        365/200           .Bad bit


11   714/732        (5 OR, 6 XR)
        Class    714 :   ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
        714/699           PULSE OR DATA ERROR HANDLING
        714/724           .Digital logic testing
```

10002499_CLSTITLES
```
       714/732          ..Signature analysis

  8  714/726        (1 OR,  7 XR)
         Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
       714/699          PULSE OR DATA ERROR HANDLING
       714/724          .Digital logic testing
       714/726          ..Scan path testing (e.g., level sensitive sca
n
                        design (LSSD))

  7  714/7          (6 OR,  1 XR)
         Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
       714/100          DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

       714/1            .Reliability and availability
       714/2            ..Fault recovery
       714/3            ...By masking or reconfiguration
       714/5            ....Of memory or peripheral subsystem
       714/6            .....Redundant stored data accessed (e.g.,
                            duplicated data, error correction coded da
ta, or other
                        parity-type data)
       714/7            ......Reconfiguration (e.g., adding a
                            replacement storage component)

  7  714/724        (2 OR,  5 XR)
         Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
       714/699          PULSE OR DATA ERROR HANDLING
       714/724          .Digital logic testing

  7  714/725        (5 OR,  2 XR)
         Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
       714/699          PULSE OR DATA ERROR HANDLING
       714/724          .Digital logic testing
       714/725          ..Programmable logic array (PLA) testing

  6  714/710        (2 OR,  4 XR)
         Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                            DETECTION/RECOVERY
       714/699          PULSE OR DATA ERROR HANDLING
       714/710          .Replacement of memory spare location, portion

                        or segment
```

Page 2

10002499_CLSTITLES

```
  6  714/711        (2 OR,  4 XR)
       Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699           PULSE OR DATA ERROR HANDLING
       714/710           .Replacement of memory spare location, portion

                              or segment
       714/711           ..Spare row or column


  6  714/719        (2 OR,  4 XR)
       Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699           PULSE OR DATA ERROR HANDLING
       714/718           .Memory testing
       714/719           ..Read-in with read-out and compare


  6  714/727        (4 OR,  2 XR)
       Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699           PULSE OR DATA ERROR HANDLING
       714/724           .Digital logic testing
       714/726           ..Scan path testing (e.g., level sensitive sca
n
                              design (LSSD))
       714/727           ...Boundary scan


  6  714/734        (0 OR,  6 XR)
       Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699           PULSE OR DATA ERROR HANDLING
       714/724           .Digital logic testing
       714/734           ..Structural (in-circuit test)


  6  714/738        (1 OR,  5 XR)
       Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                          DETECTION/RECOVERY
       714/699           PULSE OR DATA ERROR HANDLING
       714/724           .Digital logic testing
       714/738           ..Including test pattern generator


  4  324/763        (3 OR,  1 XR)
       Class    324 :  ELECTRICITY:  MEASURING AND TESTING
       324/500           FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                              ELECTRIC COMPONENTS
       324/537           .Of individual circuit component or element
       324/763           ..DUT including test circuit


  4  714/720        (2 OR,  2 XR)
```

10002499_CLSTITLES
Class   714 : ERROR DETECTION/CORRECTION AND FAULT
                DETECTION/RECOVERY
714/699   PULSE OR DATA ERROR HANDLING
714/718   .Memory testing
714/719   ..Read-in with read-out and compare
714/720   ...Special test pattern (e.g., checkerboard,
                   walking ones)

4 714/736   (0 OR, 4 XR)
   Class   714 : ERROR DETECTION/CORRECTION AND FAULT
                   DETECTION/RECOVERY
   714/699   PULSE OR DATA ERROR HANDLING
   714/724   .Digital logic testing
   714/736   ..Device response compared to expected
                      fault-free response

3 324/73.1   (1 OR, 2 XR)
   Class   324 : ELECTRICITY: MEASURING AND TESTING
   324/73.1   PLURAL, AUTOMATICALLY SEQUENTIAL TESTS

3 324/765   (1 OR, 2 XR)
   Class   324 : ELECTRICITY: MEASURING AND TESTING
   324/500   FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
                      ELECTRIC COMPONENTS
   324/537   .Of individual circuit component or element
   324/765   ..Test of semiconductor device

3 365/225.7   (1 OR, 2 XR)
   Class   365 : STATIC INFORMATION STORAGE AND RETRIEVAL
   365/189.01   READ/WRITE CIRCUIT
   365/225.7   .Having fuse element

3 714/42   (0 OR, 3 XR)
   Class   714 : ERROR DETECTION/CORRECTION AND FAULT
                   DETECTION/RECOVERY
   714/100   DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

   714/1   .Reliability and availability
   714/25   ..Fault locating (i.e., diagnosis or testing)

   714/40   ...Component dependent technique
   714/42   ....Memory or storage device component fault

3 714/6   (0 OR, 3 XR)
   Class   714 : ERROR DETECTION/CORRECTION AND FAULT
                   DETECTION/RECOVERY
   714/100   DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

714/1   .Reliability and availability
714/2   ..Fault recovery
714/3   ...By masking or reconfiguration
714/5   ....Of memory or peripheral subsystem
714/6   .....Redundant stored data accessed (e.g.,
       duplicated data, error correction coded dat
a, or other

       parity-type data)

3   714/723   (1 OR, 2 XR)
    Class   714 :   ERROR DETECTION/CORRECTION AND FAULT
          DETECTION/RECOVERY
    714/699   PULSE OR DATA ERROR HANDLING
    714/718   .Memory testing
    714/723   ..Error mapping or logging

3   714/739   (1 OR, 2 XR)
    Class   714 :   ERROR DETECTION/CORRECTION AND FAULT
          DETECTION/RECOVERY
    714/699   PULSE OR DATA ERROR HANDLING
    714/724   .Digital logic testing
    714/738   ..Including test pattern generator
    714/739   ...Random pattern generation (includes
       pseudorandom pattern)

2   365/230.03   (0 OR, 2 XR)
    Class   365 :   STATIC INFORMATION STORAGE AND RETRIEVAL
    365/230.01   ADDRESSING
    365/230.03   .Plural blocks or banks

2   365/230.06   (0 OR, 2 XR)
    Class   365 :   STATIC INFORMATION STORAGE AND RETRIEVAL
    365/230.01   ADDRESSING
    365/230.06   .Particular decoder or driver circuit

2   365/236   (0 OR, 2 XR)
    Class   365 :   STATIC INFORMATION STORAGE AND RETRIEVAL
    365/230.01   ADDRESSING
    365/236   .Counting

2   708/250   (0 OR, 2 XR)
    Class   708 :   ELECTRICAL COMPUTERS: ARITHMETIC PROCESSING
          AND CALCULATING
    708/100   ELECTRICAL DIGITAL CALCULATING COMPUTER
    708/200   .Particular function performed
    708/250   ..Random number generation

2   714/731   (0 OR, 2 XR)

```
                        10002499_CLSTITLES
        Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                         DETECTION/RECOVERY
        714/699          PULSE OR DATA ERROR HANDLING
        714/724          .Digital logic testing
        714/726          ..Scan path testing (e.g., level sensitive sca
n
                         design (LSSD))
        714/731          ...Clock or synchronization


  2  714/8           (0 OR, 2 XR)
        Class    714 :  ERROR DETECTION/CORRECTION AND FAULT
                         DETECTION/RECOVERY
        714/100          DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

        714/1            .Reliability and availability
        714/2            ..Fault recovery
        714/3            ...By masking or reconfiguration
        714/5            ....Of memory or peripheral subsystem
        714/8            .....Isolating failed storage location (e.g.,
                         sector remapping)


  2  716/16          (0 OR, 2 XR)
        Class    716 :  DATA PROCESSING:  DESIGN AND ANALYSIS OF
                         CIRCUIT OR SEMICONDUCTOR MASK
        716/1            CIRCUIT DESIGN
        716/12           .Routing (e.g., routing map, netlisting)
        716/16           ..PLA, PLD, FPGA, OR MCM
```

PLUS Search Results for S/N 10002499, Searched August 03, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search
system for U.S. Patents from 1971 to the present. PLUS is a
query-by-example search system which produces a list of patents that are
most closely related linguistically to the application searched. This
search was prepared by the staff of the Scientific and Technical
Information Center, SIRA.

6067262	6202182
6367042	6182257
6651202	6667918
6667917	5375091
5956350	5675545
5987632	5383195
5920515	5425035
6560740	5822228
6065134	5471482
5909404	6151692
6300769	6510530
6505308	5572712
6505313	5805789
6640321	5745500
6691264	6018484
6085334	6185138
6408401	5355369
6691252	6167544
5577050	6341092
5982681	6631086
6304989	5570374
6425103	5961653
5764878	5677913
5659551	5751729
6405331	6108252
6728910	6249893
5748543	5313470
6373758	5661732
6574757	5668947
5991907	5784382
6003150	5862151
5668815	5825785
6073258	5963566
4918378	6718496
5006787	5991909

5546406	5485467
5968192	6292912
6044481	5668817
5404359	5383143
5760643	5260950
5936876	5570375
5969538	5796745
5994912	5230000
6046600	5416783
6166557	5416784
6768694	5513190
6154864	5533032
6246617	5553082
6438046	5612963
6496947	5761489